

appointed as a Co-editor of *Journal of Applied Crystallography* to succeed Professor **J. C. Joubert** who has been a Co-editor of the journal since 1976. Dr Schlenker's research interests are particularly concerned with X-ray and neutron diffraction topography and other neutron diffraction studies. His full address is given on the inside front cover of the journal.

Book Reviews

Works intended for notice in this column should be sent direct to the Book-Review Editor (J. H. Robertson, School of Chemistry, University of Leeds, Leeds LS2 9JT, England). As far as practicable books will be reviewed in a country different from that of publication.

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Electron microscopy and analysis 1979. Edited by *T. Mulvey*. Pp. XVI+472. Bristol and London: The Institute of Physics, 1980. Price £23.00, US \$57.50.

This volume contains the proceedings of the 1979 conference on Electron Microscopy and Analysis held in Great Britain at the University of Sussex. The conference was organized by the Electron Microscopy and Analysis Group (EMAG) of the Institute of Physics.

These proceedings will be of interest to physical scientists who employ electron microscopy in their work. They will find this volume a good source of inspiration, since it contains work from some of the world's leading electron microscope laboratories.

The volume begins with a report of a pre-conference workshop on the definition, quantification, and measurement of 'high resolution'. This timely topic should be of interest to all electron microscopists. Fourteen invited papers and over 100 contributed papers make up the remainder of the volume. The papers were presented in sessions on: instrumentation, minerals, materials, image contrast, beam-sensitive materials, *in situ* studies, microanalysis, surface science, microanalytical techniques in surface studies, and high-resolution studies.

There are no surprises in this volume; progress in instrumentation and technique is slow, but continuing. The level of the experimental work is high, and this is a promising sign. However, electron microscopy must increase the influx of problems from the physical scientist if these trends are to continue.

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Books Received

The following books have been received by the Editor. Brief and generally uncritical notices are given of works of marginal crystallographic interest; occasionally a book of fundamental interest is included under this heading because of difficulty in finding a suitable reviewer without great delay.

Ferroelectric semiconductors. By *V. M. Fridkin* (Translated from the Russian). Pp. xiii + 318. New York: Consultants Bureau, 1980. Price US \$69.50. A review of this book, by K. M. Castelliz, has been published in the May 1981 issue of *Acta Crystallographica*, Section A, pages 447-448.

The physics and chemistry of liquid crystal devices. Edited by *G. J. Sporkel*. New York, London: Plenum Press, 1980. Price US \$42.50. A review of this book, by S. Chandrasekhar, has been published in the May 1981 issue of *Acta Crystallographica*, Section A, page 448.

Amorphous semiconductors (Topics in Applied Physics, Vol. 36). Edited by *M. H. Brodsky*. Pp. xvi + 337. Berlin: Springer, 1979. Price US \$49.50. A review of this book, by M. Inoue, has been published in the May 1981 issue of *Acta Crystallographica*, Section A, pages 446-447.